

# *A small dual-phase xenon TPC with APD and PMT readout for the study of liquid xenon scintillation*



JOHANNES GUTENBERG  
UNIVERSITÄT MAINZ



Alliance for Astroparticle Physics

**Bastian Beskers** ([beskers@uni-mainz.de](mailto:beskers@uni-mainz.de))

P. Sissol, M. Scheibelhut, C. Grignon

U. Oberlack, R. Othegraven

TIPP 2014 - Amsterdam

02 june 2014

Symmetry  
Breaking

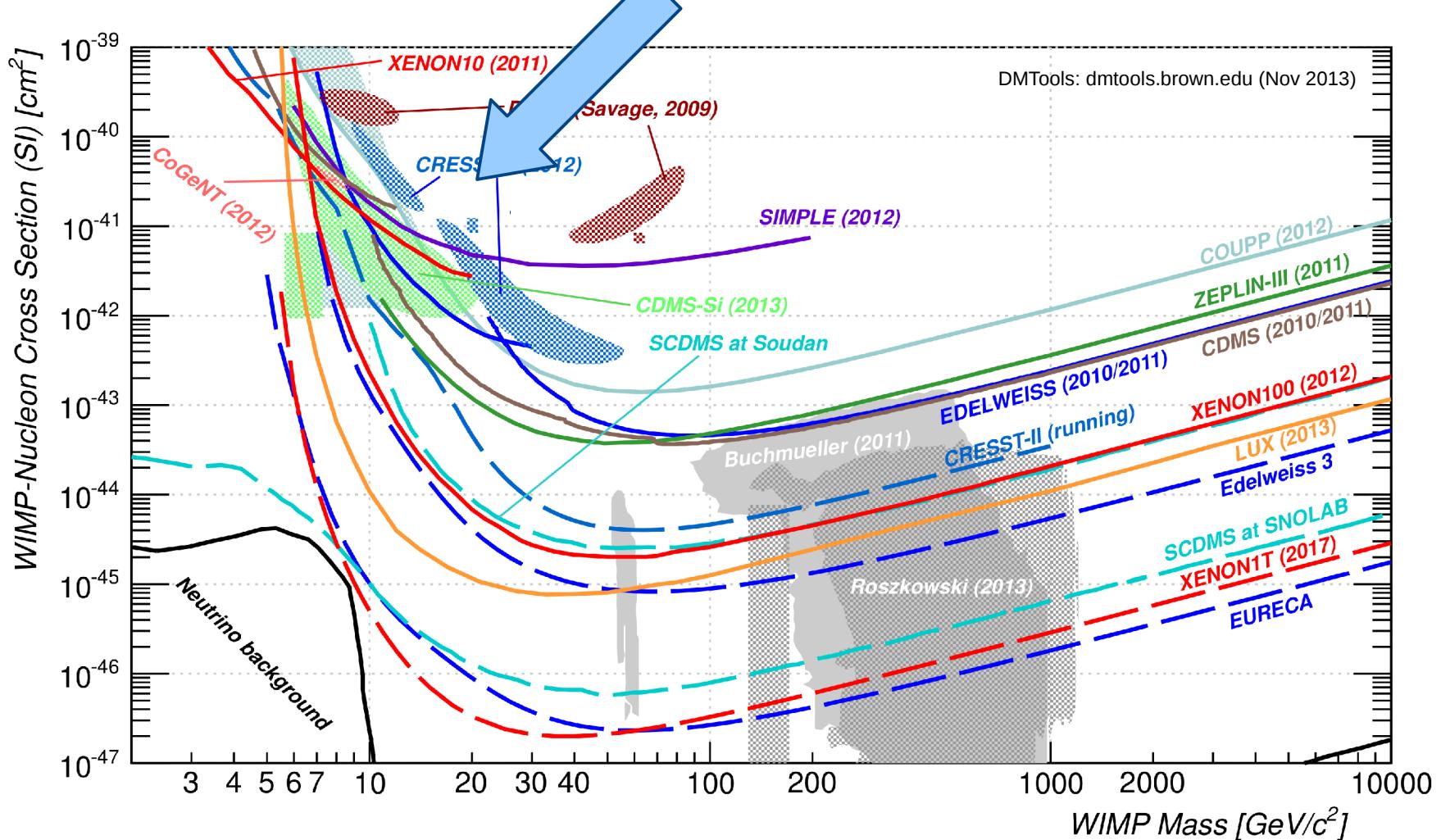


- motivation for MainzTPC
- design and status of MainzTPC
- gain and quantum efficiency  
avalanche photo diodes
- summary and outlook

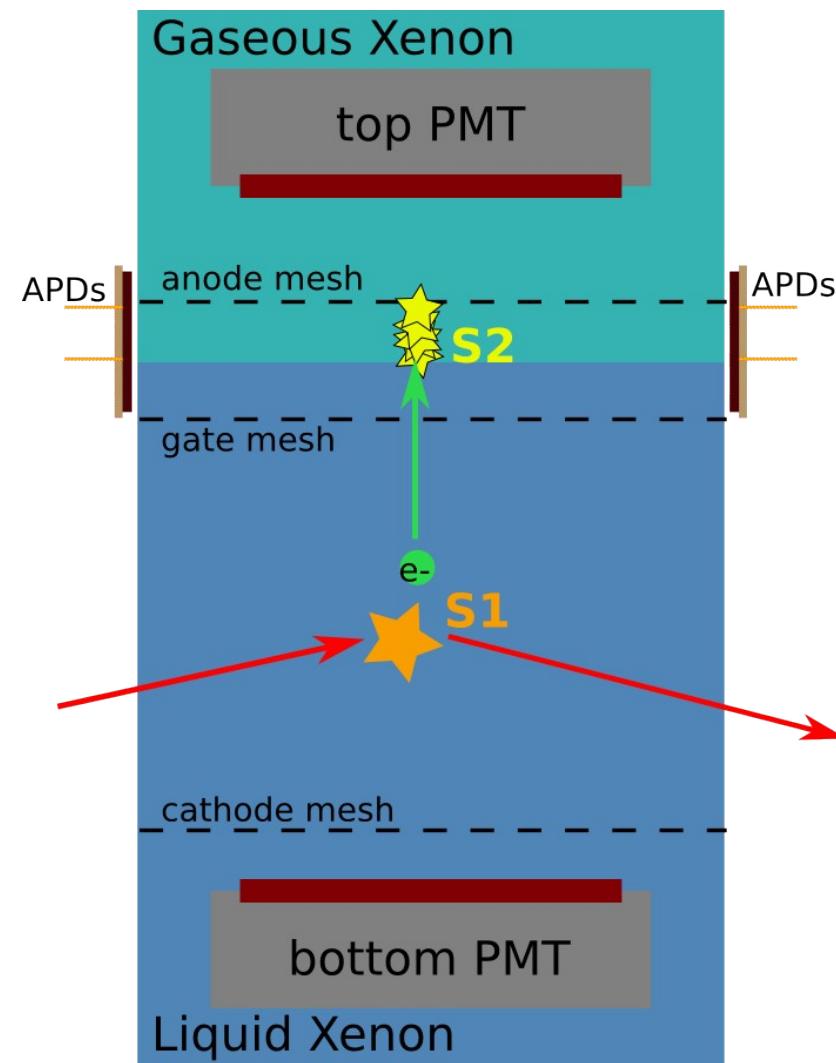


# Dark Matter results

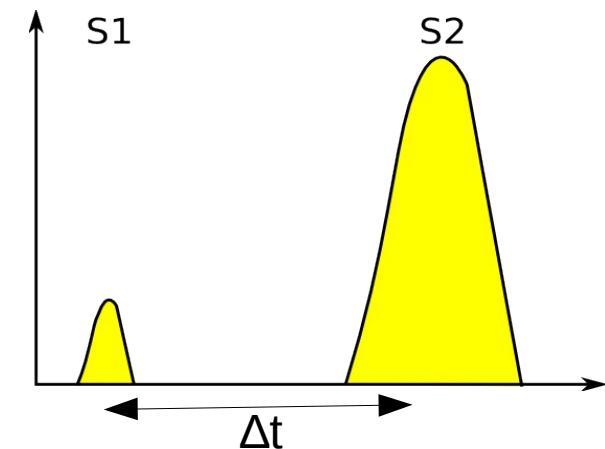
Tension in the low WIMP mass regime:  
Do we understand our detector threshold  
well?



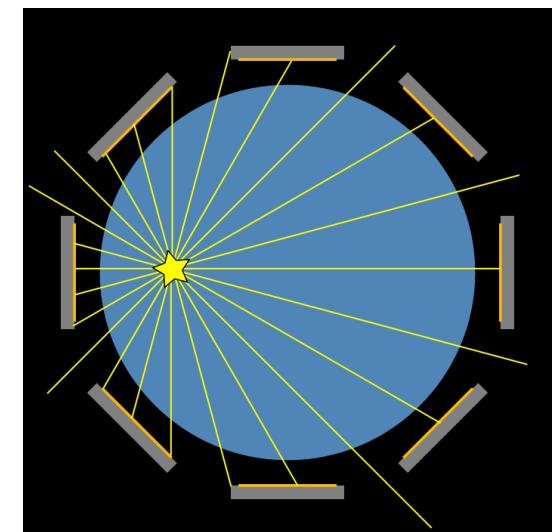
# Principle of a dual-phase xenon TPC



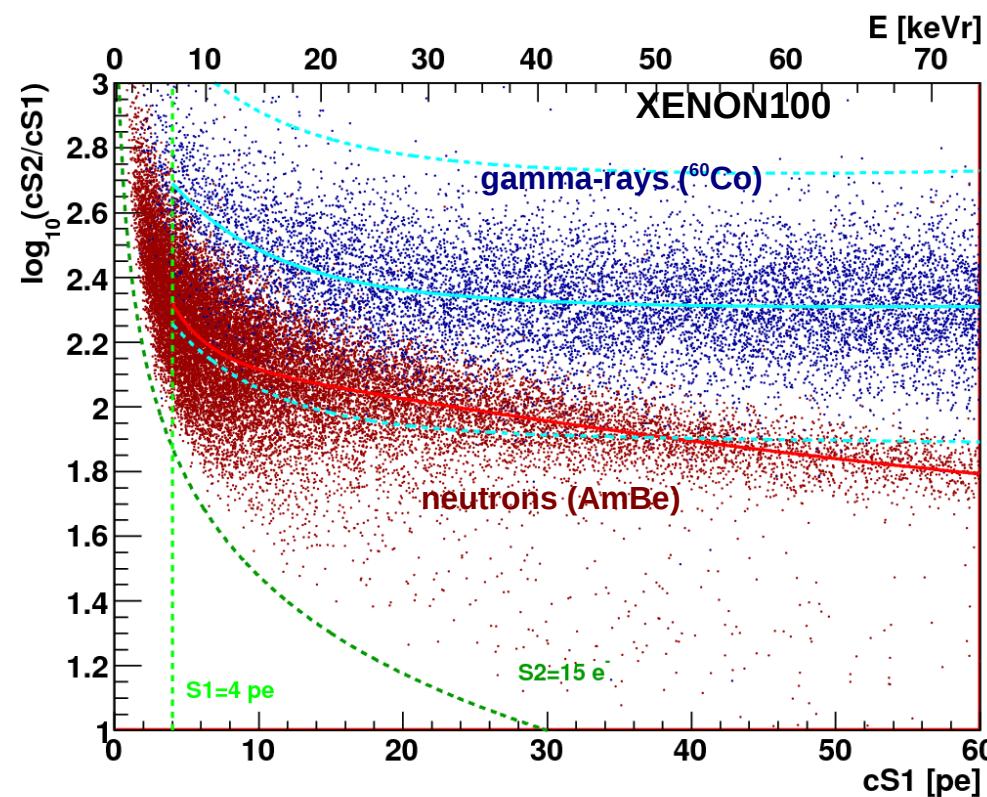
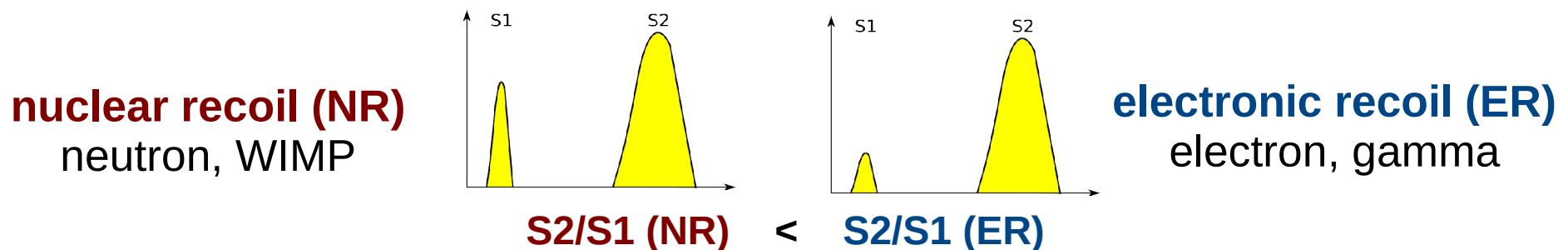
**z-position**  
reconstructed by  
electron drift time:  
$$z = \Delta t \cdot v_{\text{drift}}$$



**x/y-position**  
position of S2  
detected by a  
photosensor array

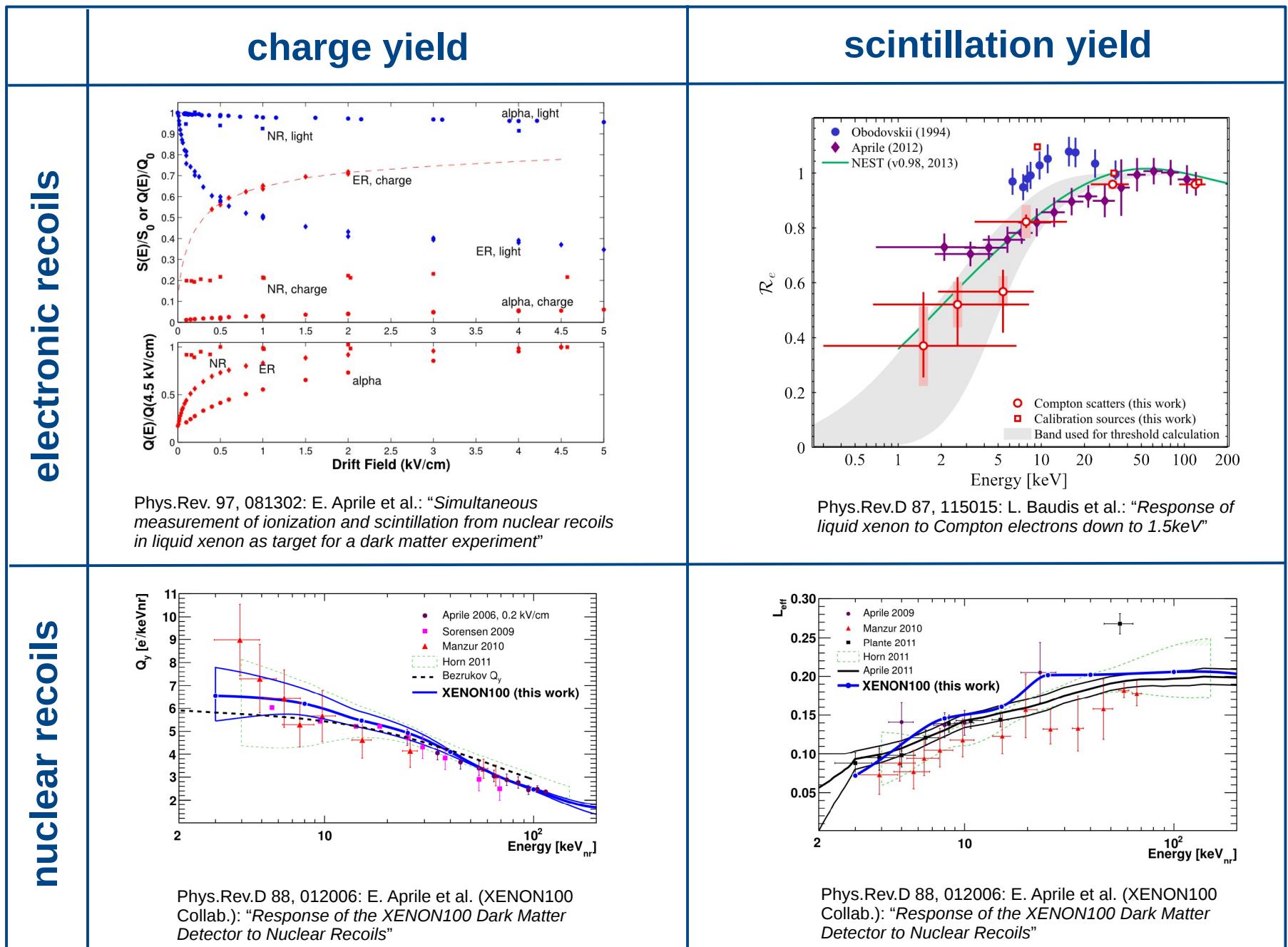


# Background discrimination in DM experiments

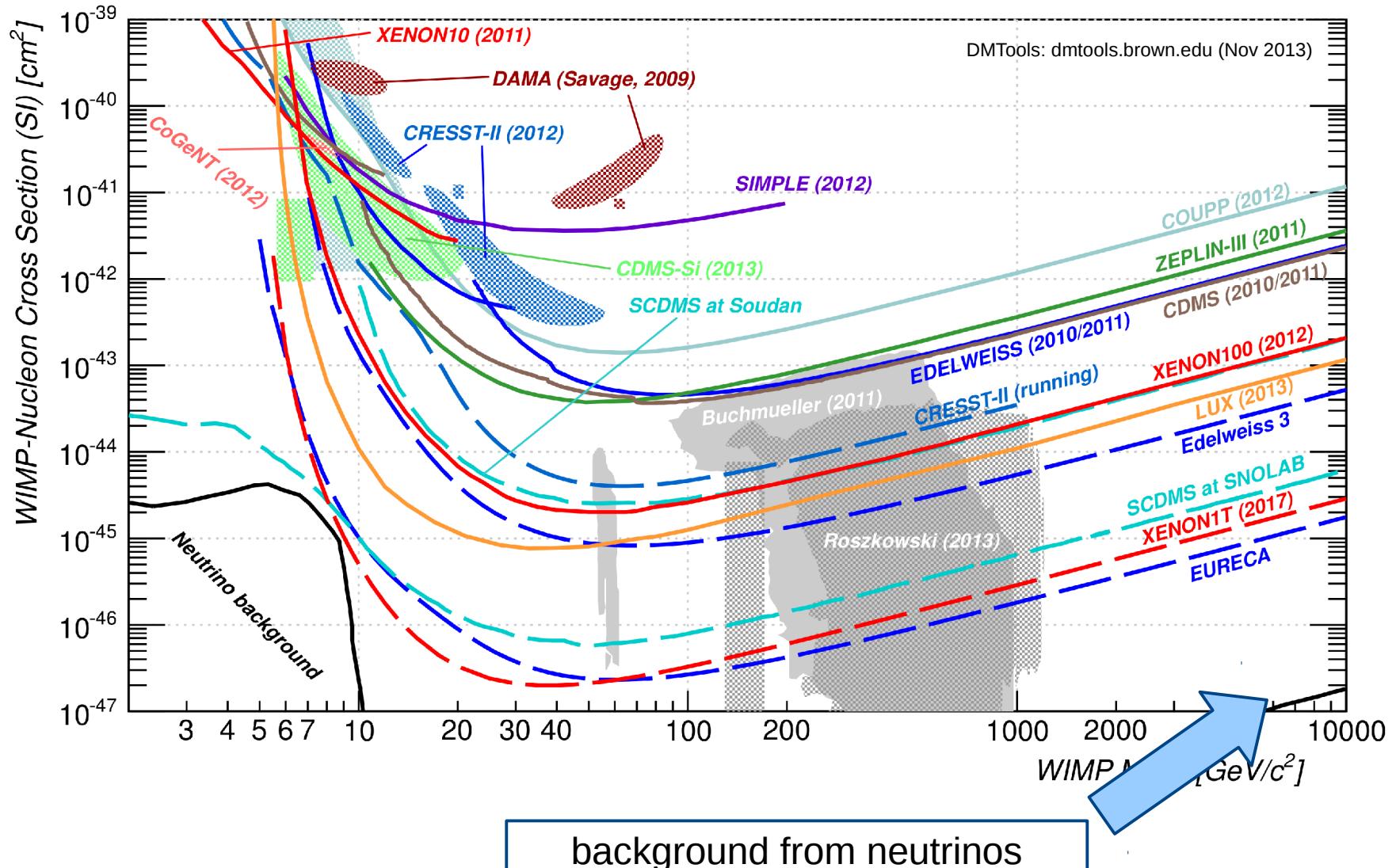


Similar in:  
2013: E. Aprile et al. (XENON100 Collab.): "Dark Matter Results from 225 Live Days from XENON100 Data"

# Charge and scintillation yield



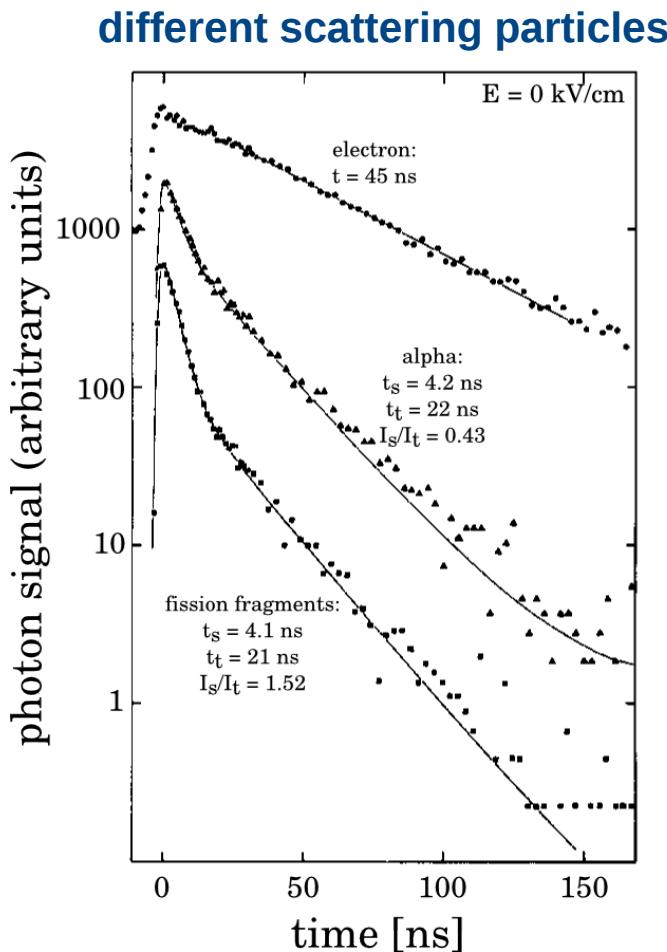
# Dark Matter results



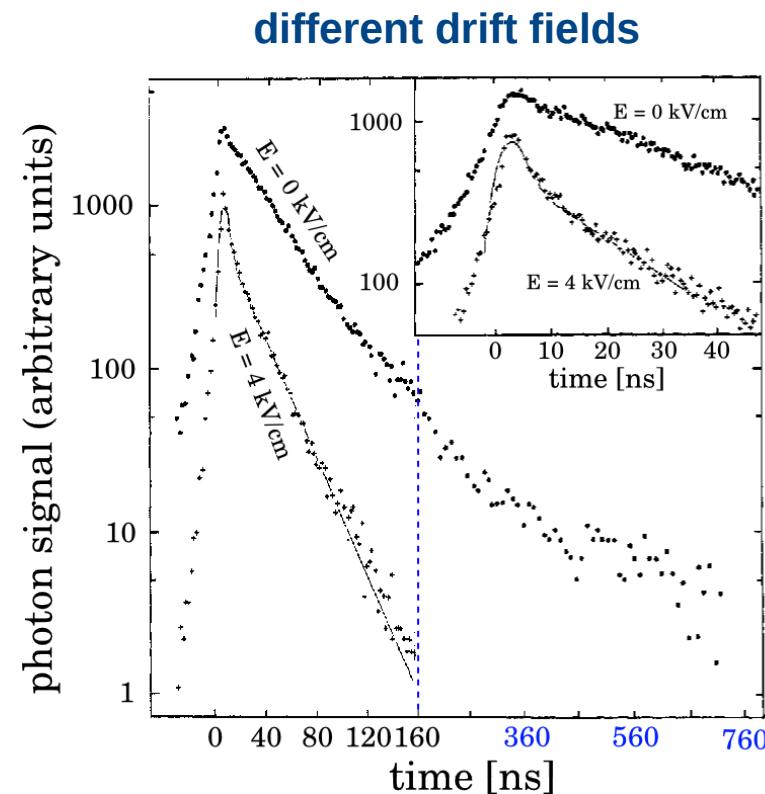
# Scintillation pulse shape

A complementary background discrimination method?

Hints from the 80's:



Physical Review B - A. Hitachi, T. Takahashi: "Effect of ionization density on the time dependence of luminescence from liquid argon and xenon"



J . Phys. C : Shinzou Kubota, Masahiko Hishida and Jian-zhi Raun: "Evidence for a triplet state of the self-trapped exciton states in liquid argon, krypton and xenon"

different time constants need  
to be disentangled



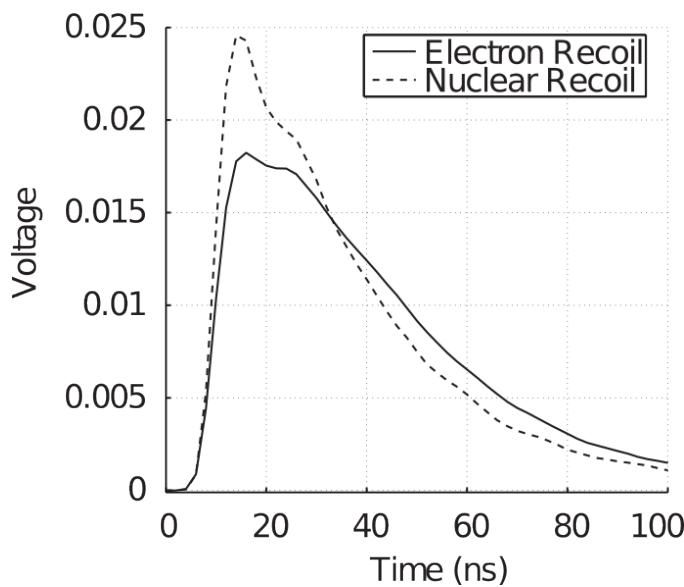
systematic tests

# Scintillation pulse shape

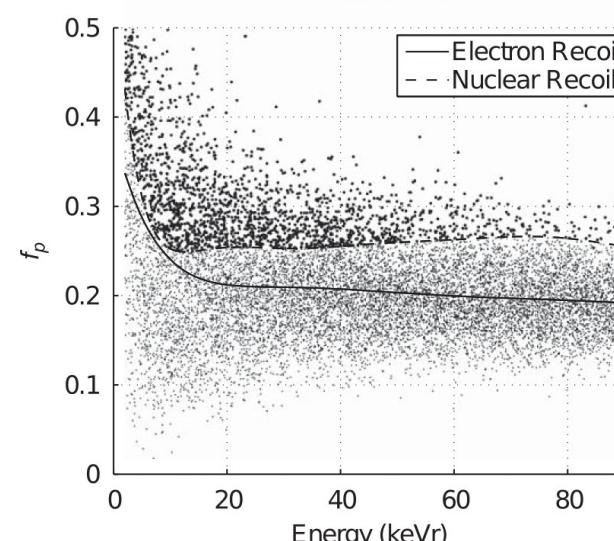
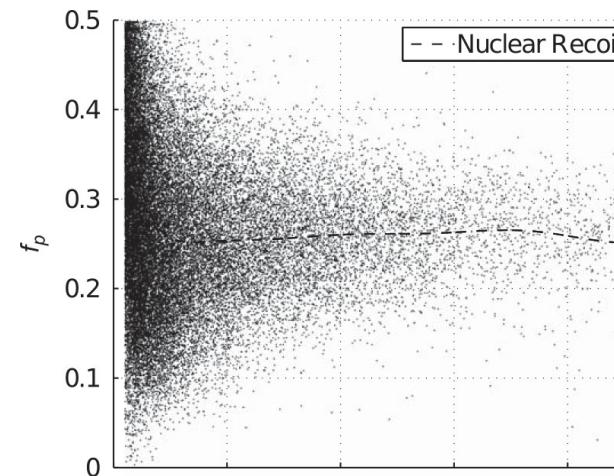
## A complementary background discrimination method?

**2010:**

pulse shape of LXe scintillation  
78keVr @ 0.06kV/cm

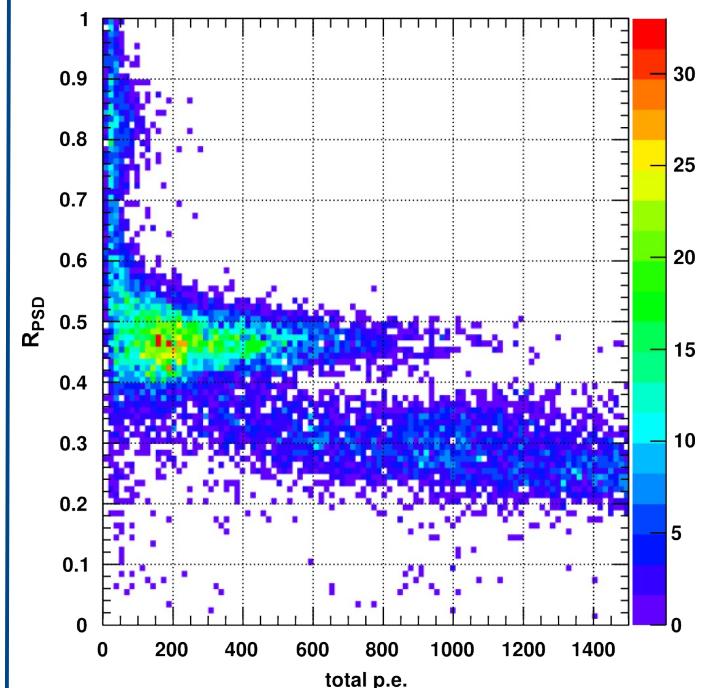


NIM A 612(2010): J. Kwong et al.: "Scintillation pulse shape discrimination in a two-phase xenon time projection chamber"



**2011:**

PSD in LXe without E-field  
Cf252 data



NIM A 659(2011): K. Ueshima et al.: "Scintillation-only based pulse shape discrimination for nuclear and electron recoils in liquid xenon"

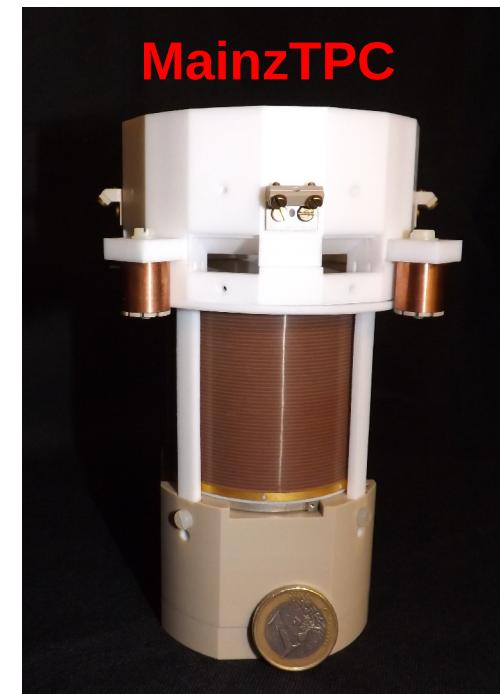
## Goal:

Measurement and understanding of low energy response of liquid xenon

- primary scintillation
- ionization
- S1 pulse shape

## Means:

- Simultaneous measurement of light and charge
- 3D position reconstruction



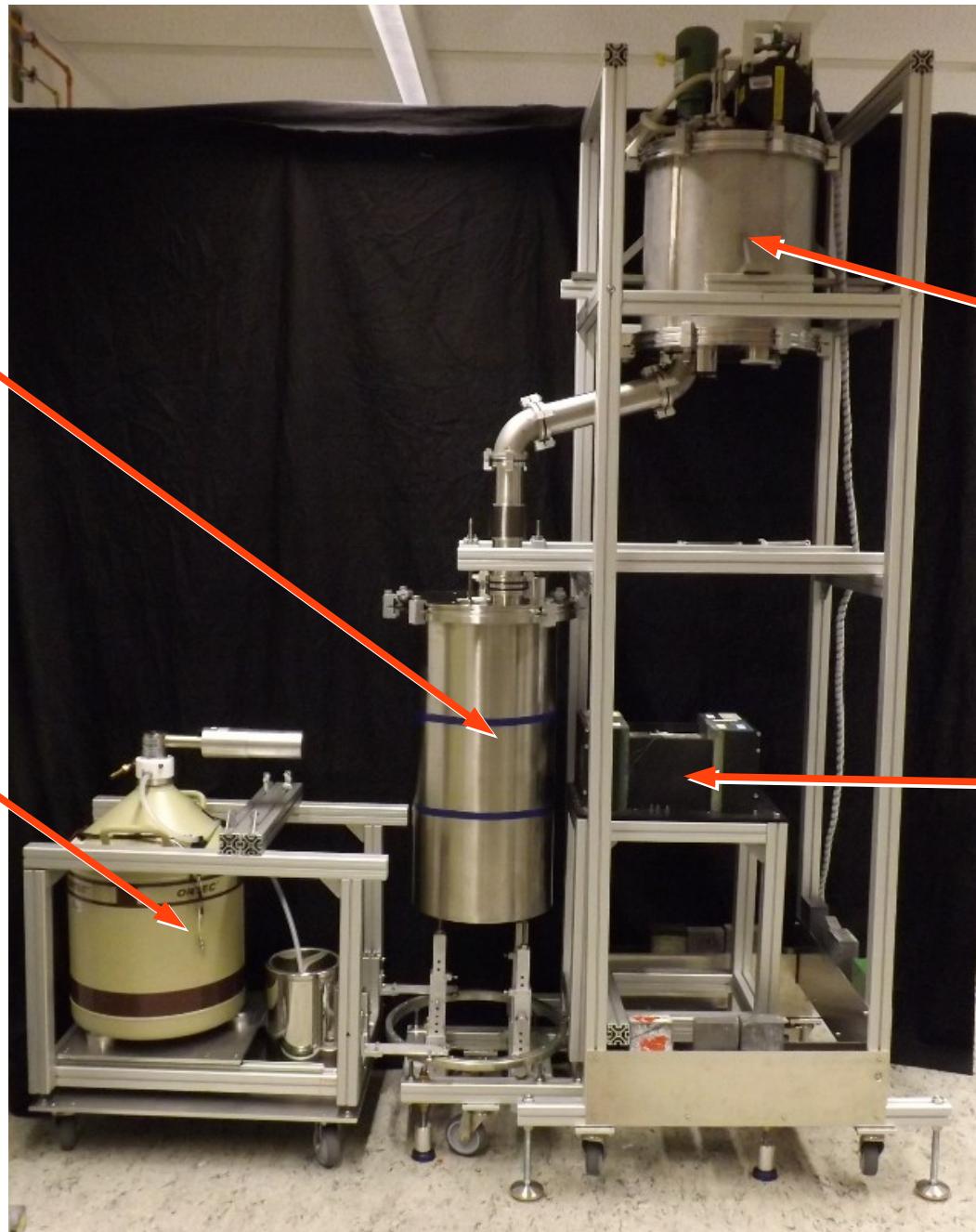
## MainzTPC:

Optimized for Compton scattering with little passive material and fast electronics.

# Cryogenic system with Compton setup

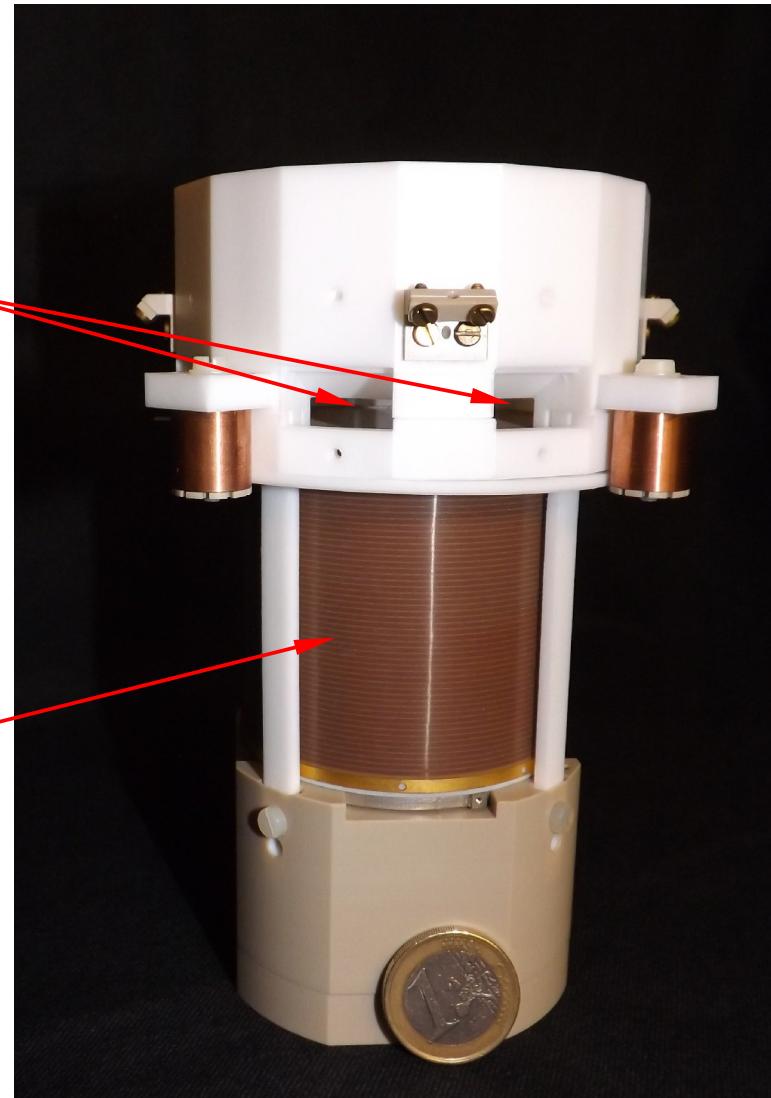
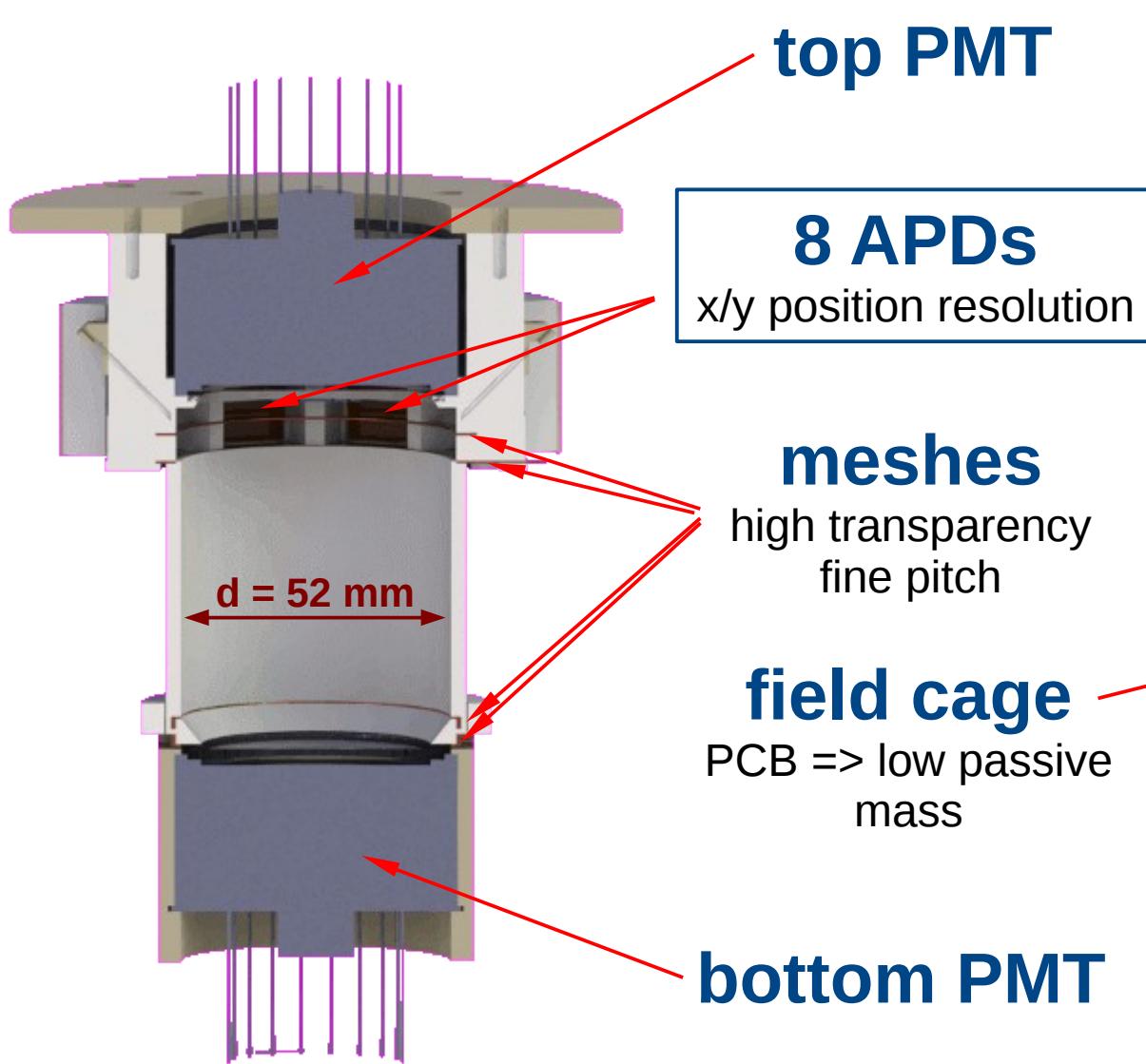


# Cryogenic system with Compton setup

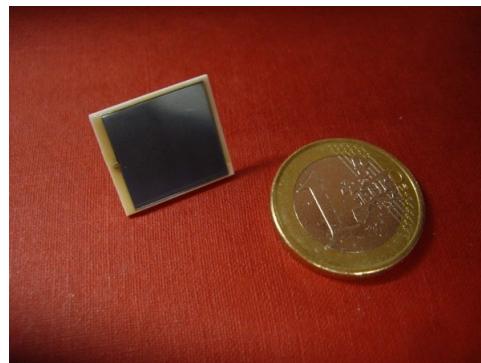
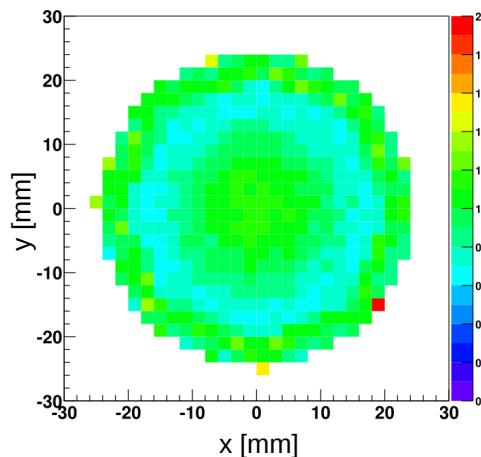


**pulse tube  
refrigerator +  
LN2 emergency  
cooling**

**collimator for  
 $\gamma$ -source**

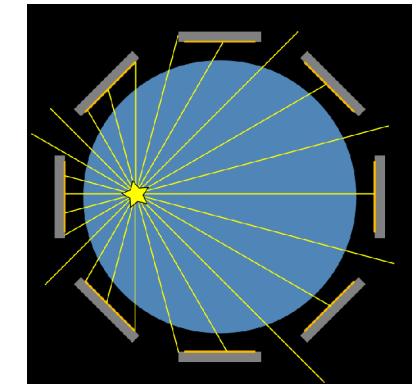


# Avalanche Photo Diodes: RMD S1315



## position reconstruction:

- G4: resolution < 1.3 mm
- using relative amount of light seen by each APD

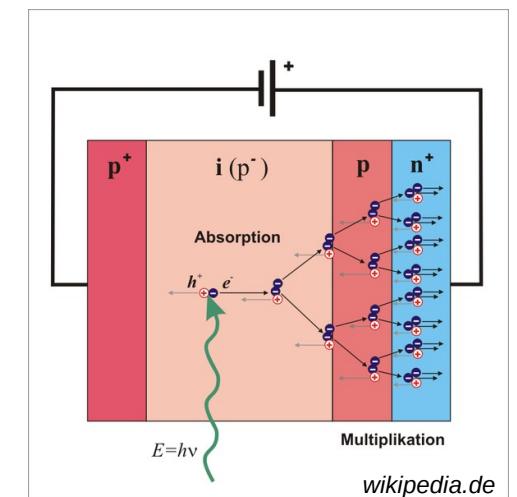


## RMD S1315:

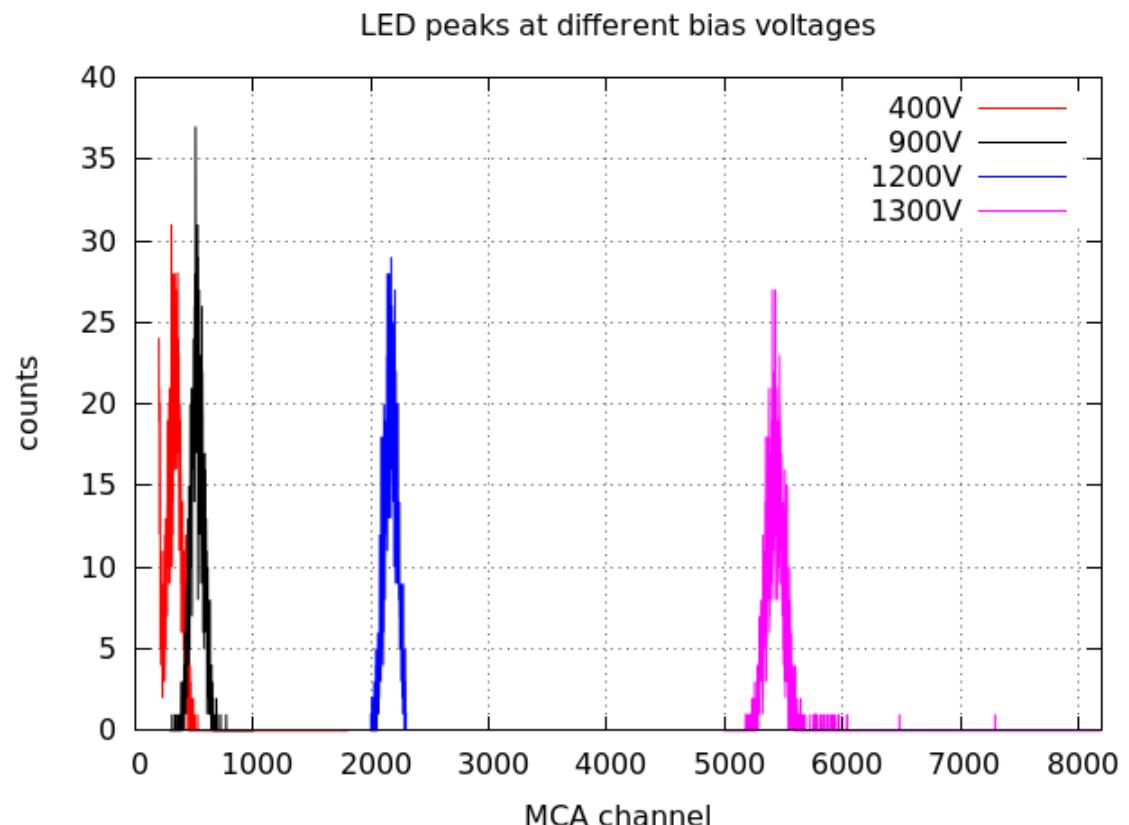
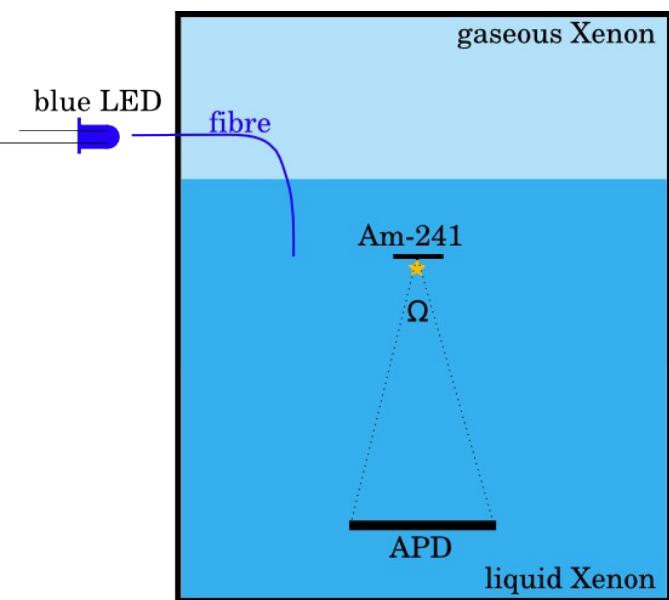
- active area: 14x14 mm<sup>2</sup>
- no housing - little passive material
- QE ~ 30% @ 178 nm  
(P. Shagin et al 2009 JINST 4 P01005)

## What are APDs?

- photo diodes with internal gain (typically  $\sim 10^2\text{-}10^3$ )
- gain depending on temperature and bias voltage



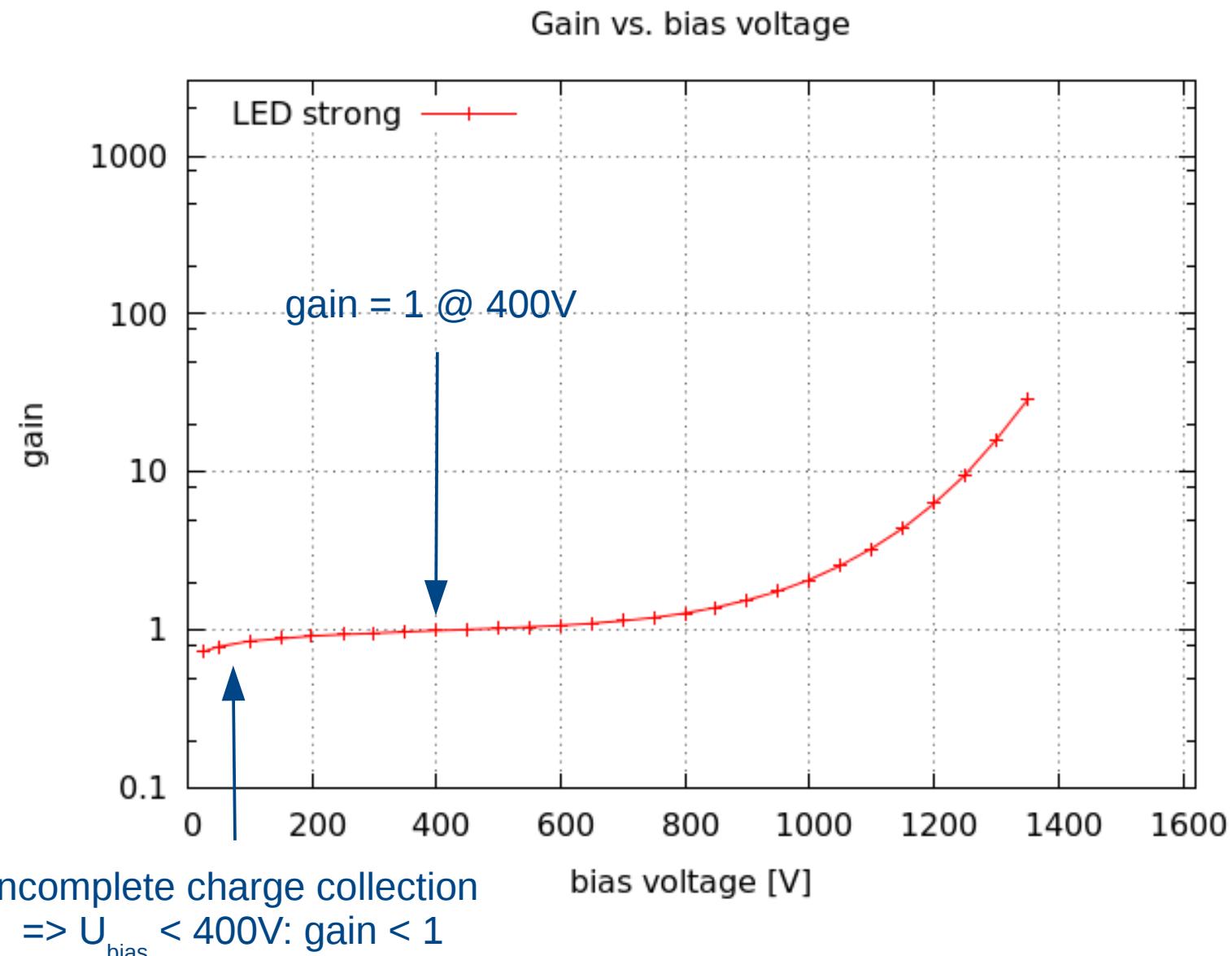
# APDs: gain measurement



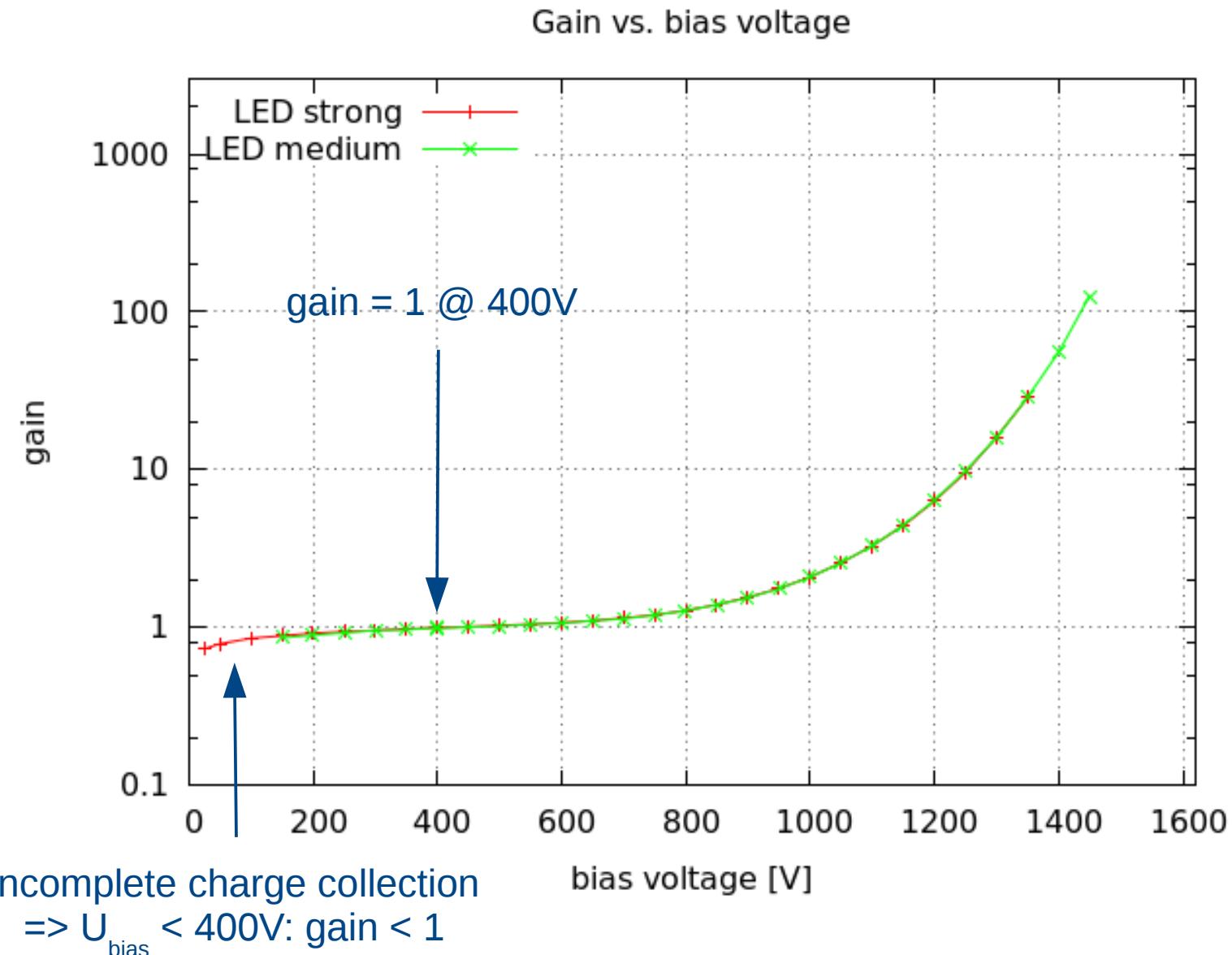
## gain measurement:

- pulsed blue LED
- measure spectra at different bias voltages
- using different strength of LED pulses to cover full gain range

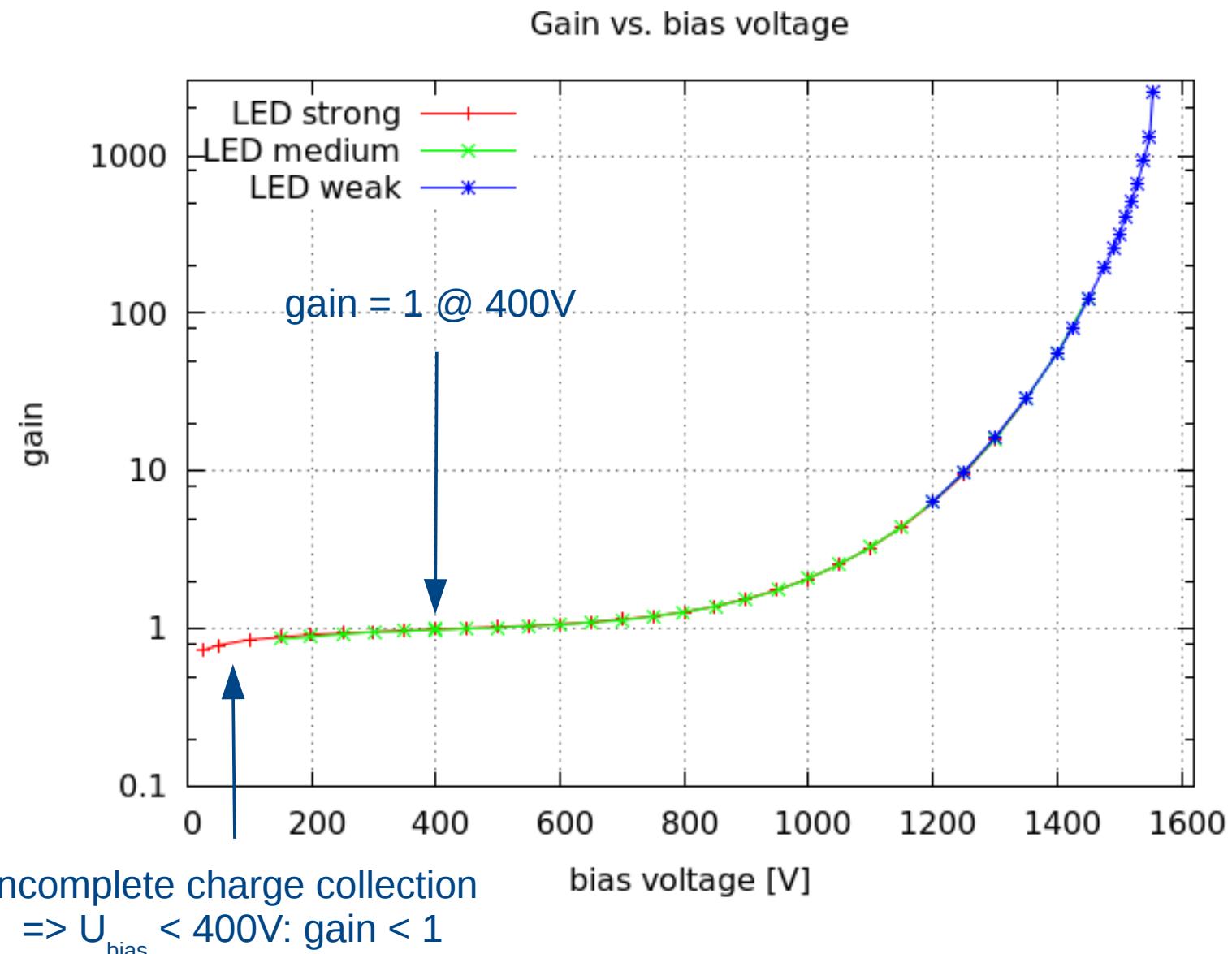
# gain vs. bias voltage - reference APD



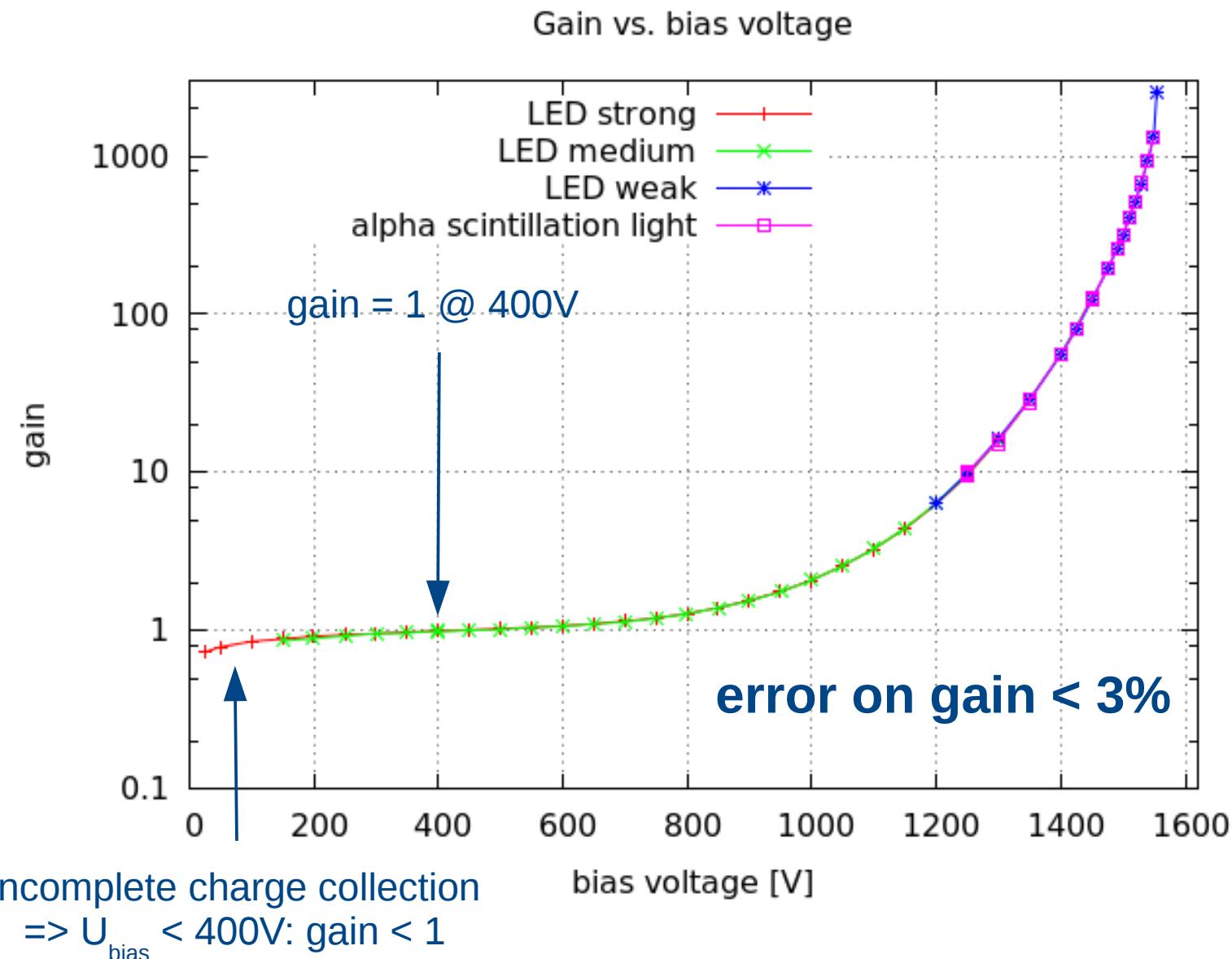
# gain vs. bias voltage - reference APD



# gain vs. bias voltage - reference APD



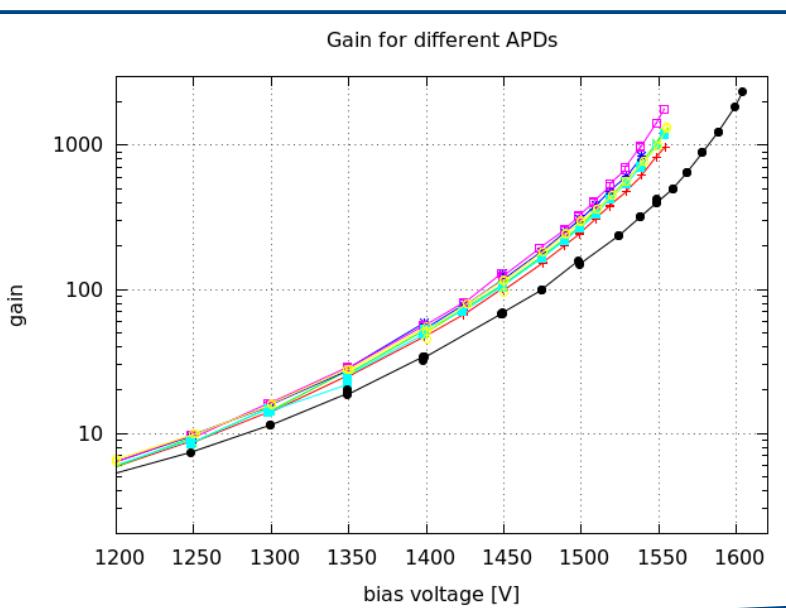
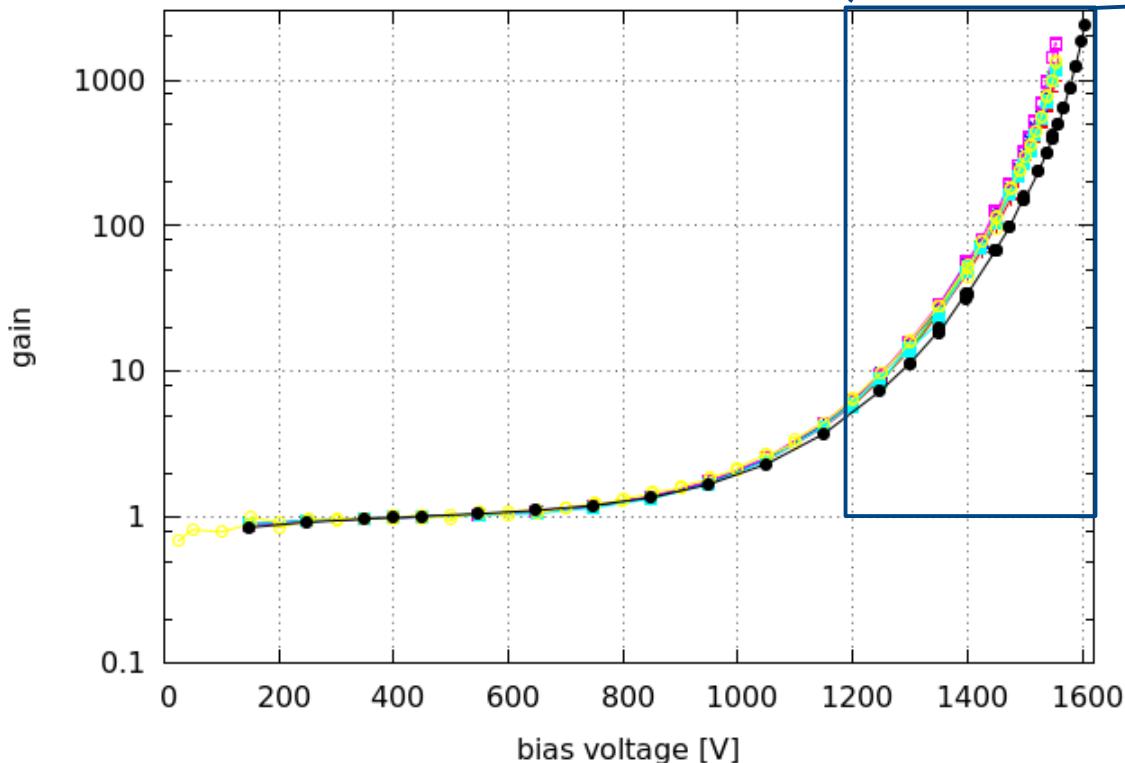
# gain vs. bias voltage - reference APD



# gain vs. bias voltage - all APDs

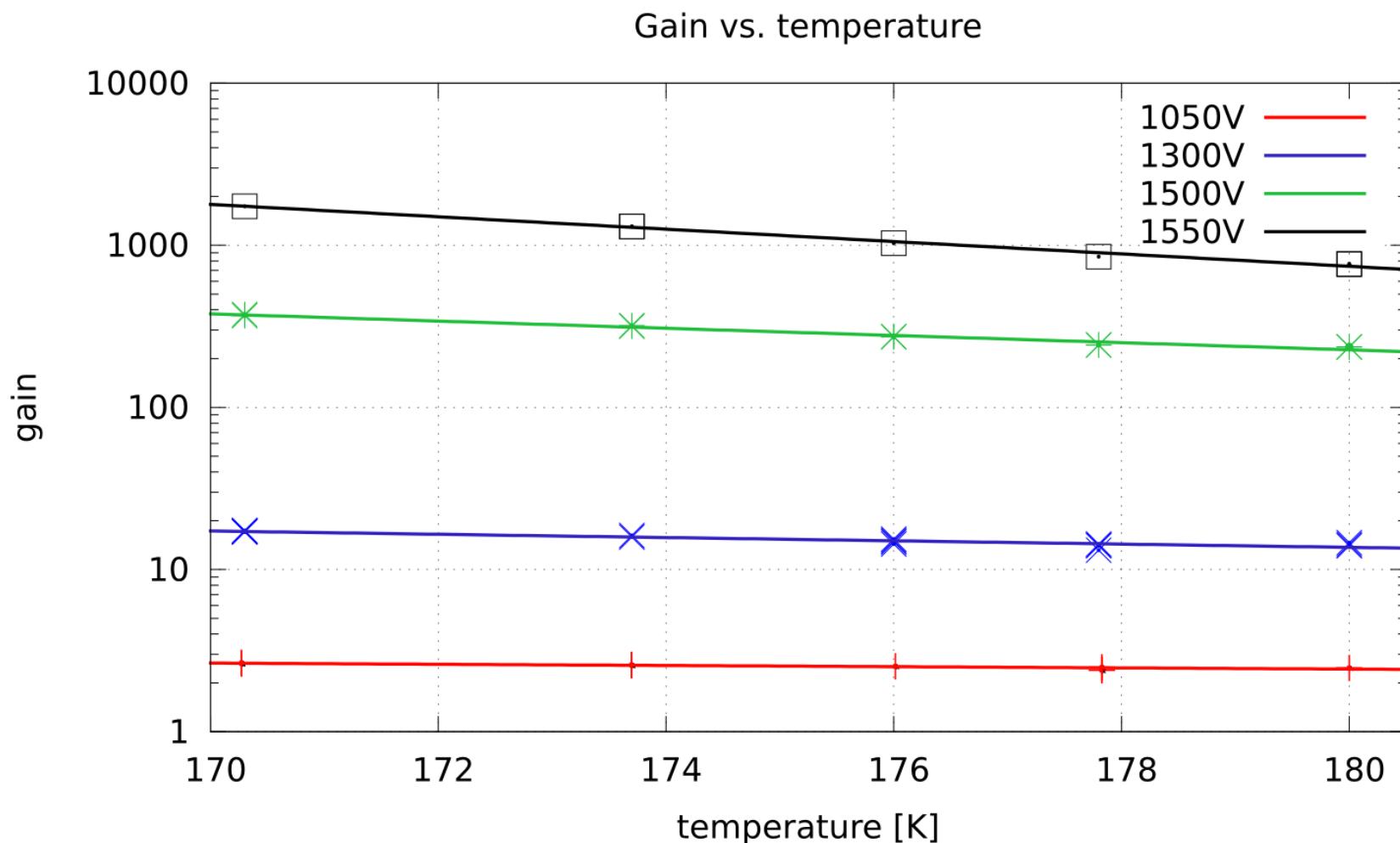
**colors:** APDs from wafer A  
**black:** APD from wafer B

Gain for different APDs



$$T = 176.3 \text{ K} \pm 0.3 \text{ K}$$
$$\Delta T < 0.1 \text{ K} \text{ for each APD}$$

# gain vs. temperature: reference APD



$$g(T) = g_0 \cdot \exp(-k_0 \cdot (T - T_0))$$

fixed Parameter:  $T_0 = 170.3\text{ K}$

free parameters:  $g_0, k_0$

$$k_0 = \frac{\partial \log(g)}{\partial T}$$

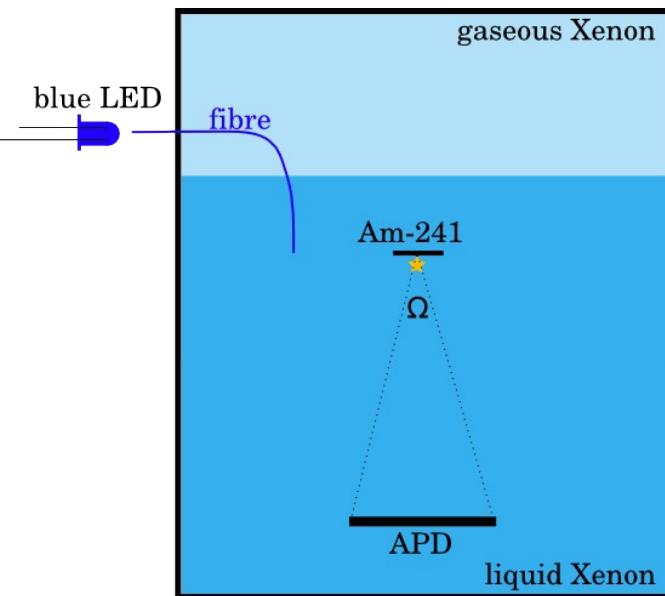
$$k_0(1050\text{V}) = 0.0085$$

$$k_0(1300\text{V}) = 0.0232$$

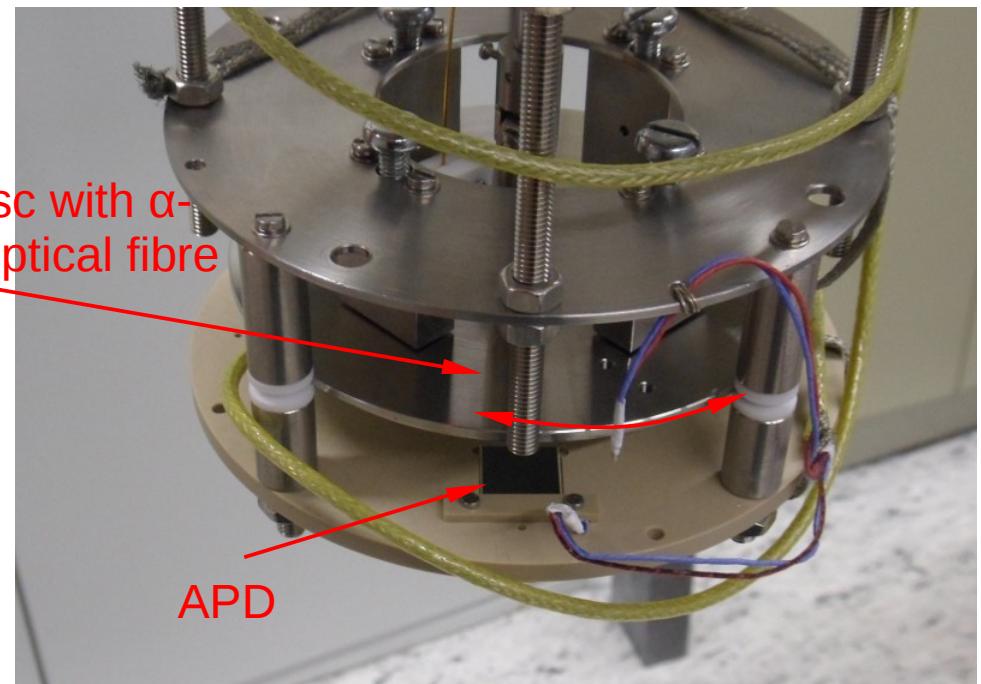
$$k_0(1500\text{V}) = 0.0510$$

$$k_0(1550\text{V}) = 0.0879$$

# APDs: measuring QE @ 178nm



rotatable disc with  $\alpha$ -source and optical fibre

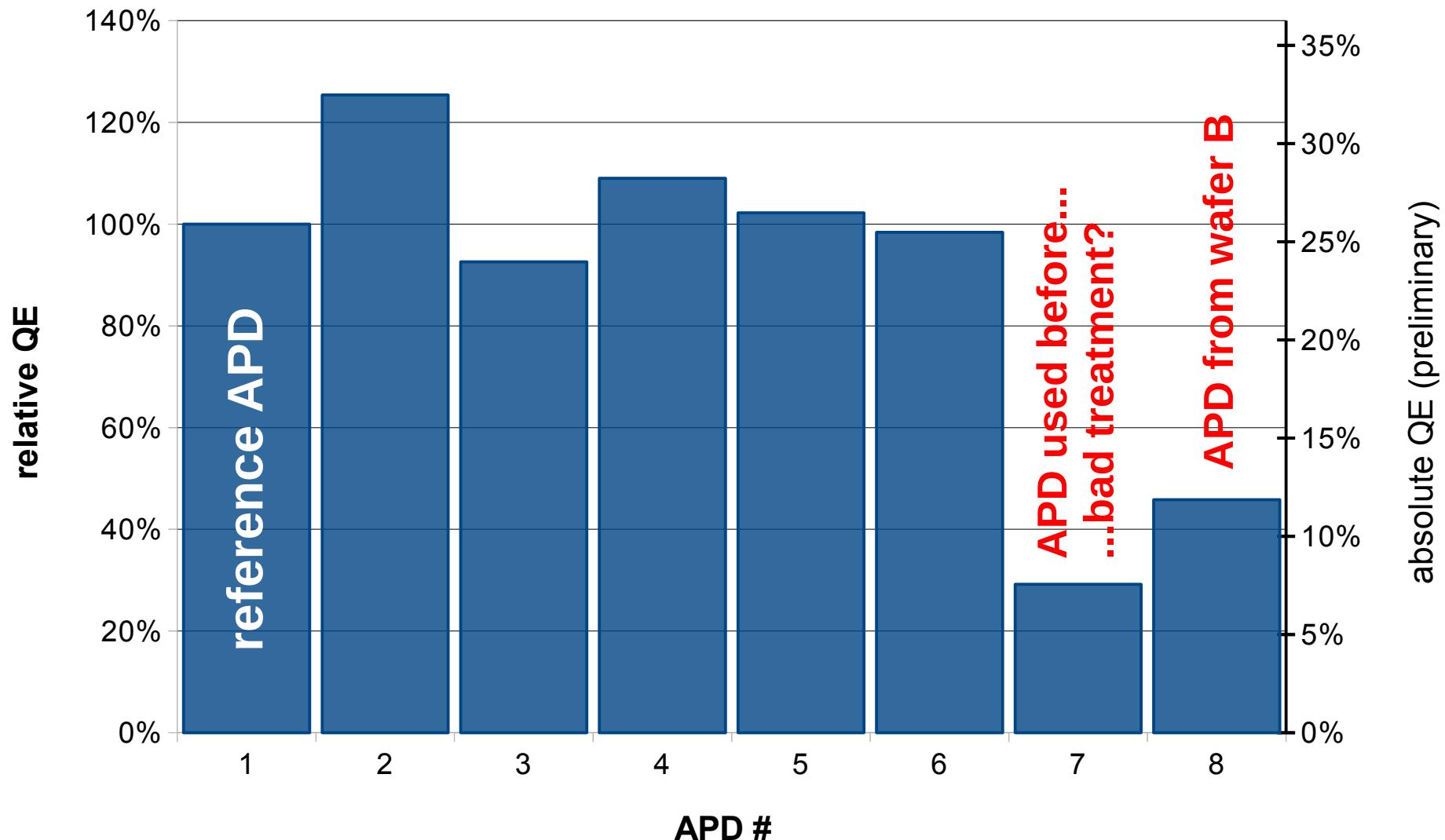


## QE calculation depends on:

- number of photons generated
- solid angle
- APD gain

$$QE = \frac{N_{\gamma}^{measured}}{N_{\gamma}^{hit}} = \frac{\frac{Q_{measured}}{gain \cdot e}}{N_{\gamma}^{hit}}$$

# APD quantum efficiencies



# Summary

- TPC optimized for Compton scatter experiment built
- Compton setup built up
- light detectors characterized (APDs)
- commissioning next weeks
- measurement of light/charge yield for electron recoils this summer
- measurement of scintillation pulse shape for electron recoils this summer

**Thanks to all collaborators:**

Pierre Sissol  
Melanie Scheibelhut  
Rainer Othegraven  
Christopher Hils  
Dr. Cyril Grignon  
Prof. Uwe Oberlack

Bastian Beskers  
[beskers@uni-mainz.de](mailto:beskers@uni-mainz.de)  
TIPP 2014 - Amsterdam  
02. june 2014

# QUESTIONS?

## Thanks to all collaborators:

Pierre Sissol  
Melanie Scheibelhut  
Rainer Othegraven  
Christopher Hils  
Dr. Cyril Grignon  
Prof. Uwe Oberlack

Bastian Beskers  
[beskers@uni-mainz.de](mailto:beskers@uni-mainz.de)  
TIPP 2014 - Amsterdam  
02. june 2014

# Readout system

## Struck SIS3305

- 10 bit FADC
- 2/4/8 channels
- 5/2.5/1.25 GS/s
- 1.5 GHz bandwidth



*digitize PMT signal with  
good time-resolution*

## Struck SIS3316

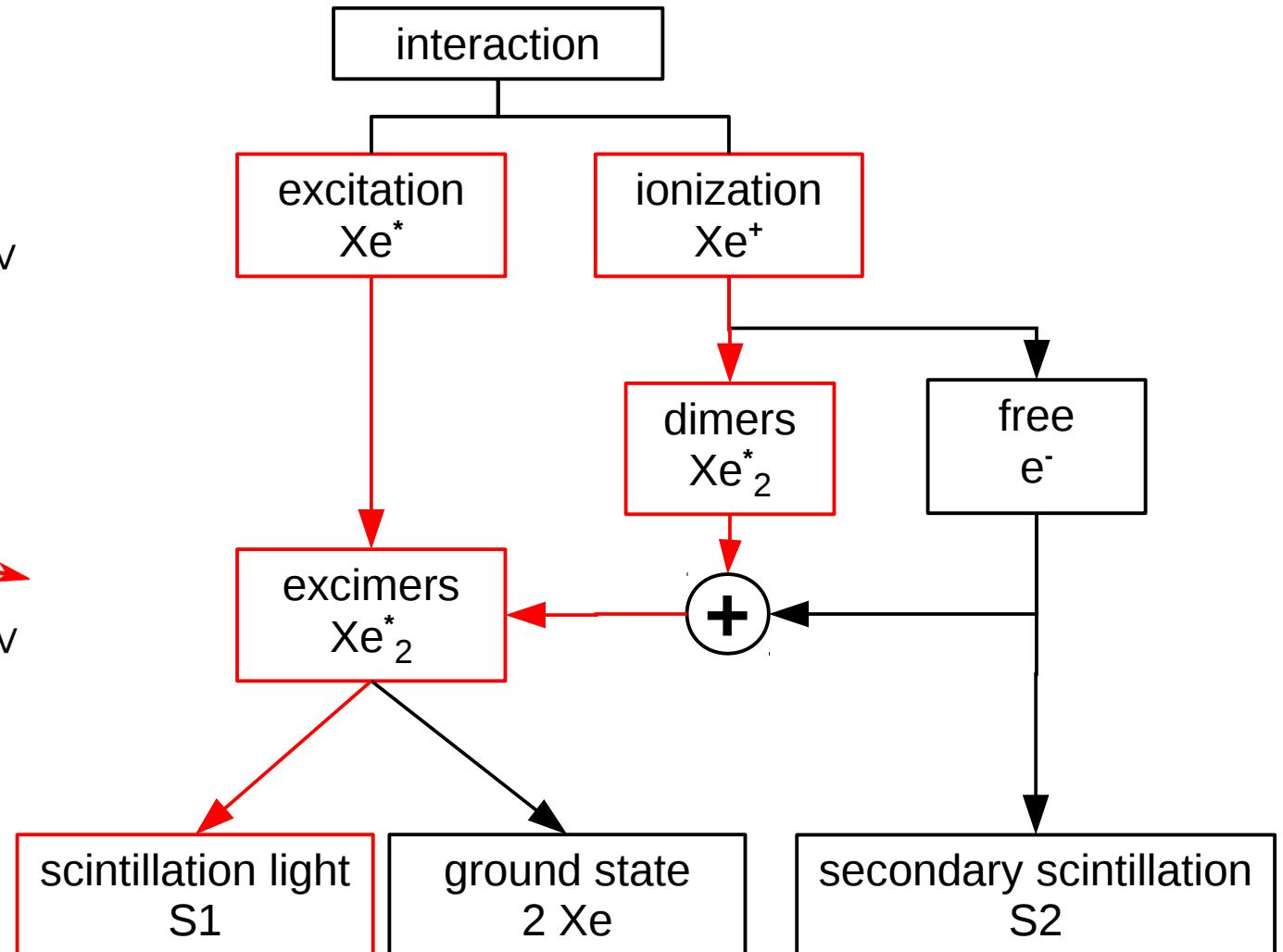
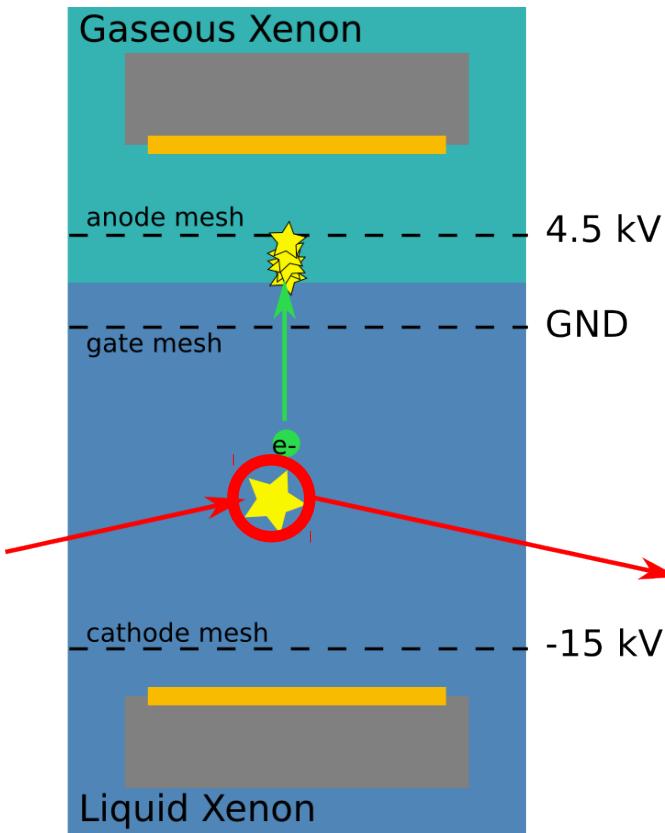
- 16 bit FADC
- 16 channels
- 125 MS/s
- 62.5 MHz bandwidth



*digitize Ge-detector and  
APDs with good energy-  
resolution*

# principle dual-phase TPC

## S1: primary scintillation



# table of measured QEs

APD	realitive QE	absolute QE
426-2-7 (reference)	100 %	25.9 %
426-2-1	29.2 %	7.6 %
426-2-3	125.4 %	32.5 %
426-2-4	92.6 %	24.0 %
426-2-5	109 %	28.2 %
426-2-9	102.2 %	26.5 %
393-3-10	45.8 %	11.9 %



used before;  
maybe bad treatment



different wafer